

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10585655	TAKUMAI ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	DEVONA E FAULK	2615

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
381	27,1,17,92,111,122,18,335	8/20/08	DEF
381	27,1,17,92,111,335,95-97,18	4/22,25/10	DEF
381	27,1,17,92,111,335,95-97,18,19,300,307,80	9/30/10,9/28/11	DEF
381	27,1,17,92,111,335,95-97,18,19,300,307,80	1/27/12	DEF

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
assignee/inventor search	8/20/08	DEF
combined class/word search	8/20/08	DEF
additional search	4/22/10	DEF
additonal search	9/30/10,9,21,22, 26,28/11	DEF
additional search	1/27/12	DEF

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	combined class/word search	9/28/11	DEF
	combined class/word search	1/27/12	DEF

	/DEVONA E FAULK/ Primary Examiner.Alt Unit 2614
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